Dkt: 884.410US1

Serial Number: 09 838730 Filing Date: April 19, 2001

Title: AC TESTING OF 1 FAKAGE CURRENT IN INTEGRATED CIRCUITS USING RC TIME CONSTANT (As Amended)

## IN THE ABSTRACT OF THE DISCLOSURE

Please amend the Abstract as follows:

## **Abstract of the Disclosure**

A method of leakage test for testing an integrated circuit includes applying a voltage to one of the pins of the integrated circuit. The pin is floated for a predetermined time. A measurement is performed after the predetermined time. The measurement involves by sampling the RC time constant of leakage current of the pins of the integrated circuit.